## MSKSEMI















**ESD** 

TVS

TSS

MOV

GDT

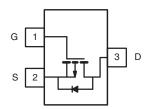
**PLED** 

# Broduct data sheet





SOT-23



#### **Features**

- $-30V, -0.2A, RDS(ON) = 4.0\Omega@VGS = -10V$
- Improved dv/dt capability
- Fast switching
- Green Device Available

#### **Applications**

- Notebook
- Load Switch
- Battery Protection
- Hand-held Instruments

BVDSS	RDSON	ID
-30V	4.0Ω	-0.2A

#### **Absolute Maximum Ratings** Tc=25°C unless otherwise noted

Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	-30	V
V <sub>G</sub> S	Gate-Source Voltage	±20	V
1-	Drain Current – Continuous (T <sub>A</sub> =25°C)	-0.2	А
ID	Drain Current – Continuous (T <sub>A</sub> =70°C)	-0.1	А
I <sub>DM</sub>	Drain Current – Pulsed <sup>1</sup>	-0.8	А
D-	Power Dissipation (T <sub>A</sub> =25°C)	1.0	W
P <sub>D</sub>	Power Dissipation – Derate above 25°C	12.5	mW/°C
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	℃
TJ	Operating Junction Temperature Range	-55 to 150	°C

#### **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Unit
R <sub>0JA</sub>	Thermal Resistance Junction to ambient		80	°C/W



#### **Electrical Characteristics** (T<sub>J</sub>=25 °C, unless otherwise noted)

#### **Off Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
$BV_{DSS}$	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA	-30			V
lana	Drain-Source Leakage Current	V <sub>DS</sub> =-30V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			-1	uA
IDSS	Diain-Source Leakage Current	V <sub>DS</sub> =-25V , V <sub>GS</sub> =0V , T <sub>J</sub> =125°C			<b>-</b> 10	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> =±20V , V <sub>DS</sub> =0V			±20	uA

#### **On Characteristics**

Prevent		V <sub>GS</sub> =-10V , I <sub>D</sub> =-0.2A		4.0	8.0	0	
R <sub>DS(ON)</sub>		V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-0.1A		8.0	10	Ω	
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =-250uA	<b>-</b> 1.0	<b>-</b> 1.6	<b>-</b> 2.5	V	
gfs	Forward Transconductance	V <sub>DS</sub> =-10V , I <sub>D</sub> =-0.2A		0.4		S	

#### **Dynamic and switching Characteristics**

$Q_g$	Total Gate Charge <sup>2, 3</sup>		 2.8	
$Q_{gs}$	Gate-Source Charge <sup>2, 3</sup> V <sub>DS</sub> =-30V , V <sub>GS</sub> =-10V , I <sub>D</sub> =-0.2A		 0.96	 nC
$Q_{gd}$	Gate-Drain Charge <sup>2, 3</sup>		 0.6	
T <sub>d(on)</sub>	Turn-On Delay Time <sup>2, 3</sup>		 3	
Tr	Rise Time <sup>2, 3</sup> $V_{DD}$ =-30V , $V_{GS}$ =-10V , $R_G$ =6 $\Omega$		 5	 no
T <sub>d(off)</sub>	Turn-Off Delay Time <sup>2, 3</sup>	I <sub>D</sub> = <b>-</b> 0.2A	 14	 ns
T <sub>f</sub>	Fall Time <sup>2, 3</sup>		 9	
Ciss	Input Capacitance		 30.5	
Coss	Output Capacitance V <sub>DS</sub> =-30V , V <sub>GS</sub> =0V , F=1MHz		 15.1	 pF
C <sub>rss</sub>	Reverse Transfer Capacitance		 7	

#### **Drain-Source Diode Characteristics and Maximum Ratings**

Symbol	Parameter	Parameter Conditions		Тур.	Max.	Unit
Is	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			-0.2	Α
Ism	Pulsed Source Current	VG-VD-UV , Force Current			-0.4	Α
V <sub>SD</sub>	Diode Forward Voltage	V <sub>GS</sub> =0V , I <sub>S</sub> =-0.2A , T <sub>J</sub> =25°C			-1.3	V
Trr	Reverse Recovery Time	covery Time VR=-30V, IS=-0.2A		13.5		nS
Q <sub>rr</sub>	Reverse Recovery Charge	di/dt=100A/µs, TJ=25℃		3		nC

#### Note:

- 1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
- 2. The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%.
- 3. Essentially independent of operating temperature.



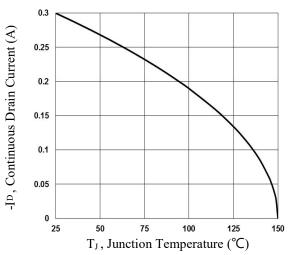


Fig.1 Continuous Drain Current vs. Tc

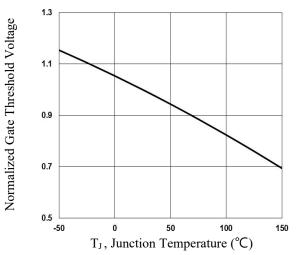


Fig.3 Normalized Vth vs. TJ

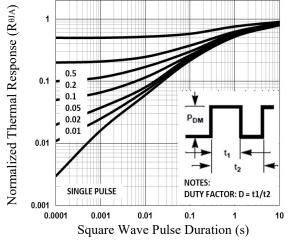


Fig.5 Normalized Transient Impedance

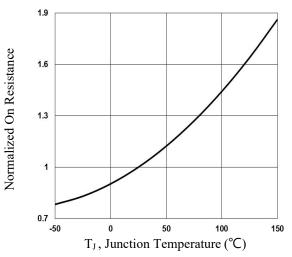


Fig.2 Normalized RDSON vs. TJ

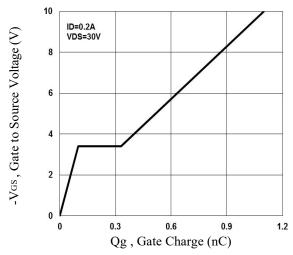


Fig.4 Gate Charge Waveform

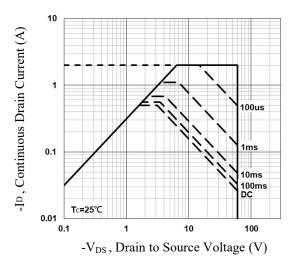
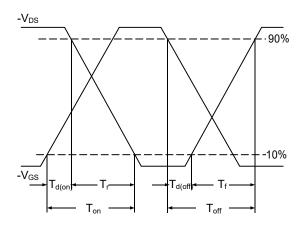


Fig.6 Maximum Safe Operation Area





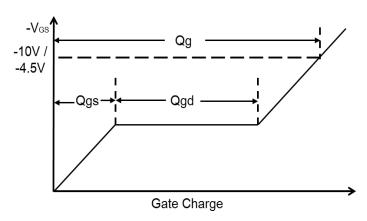
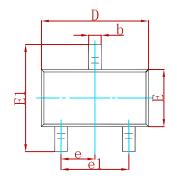


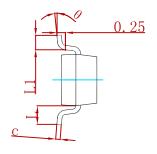
Fig.7 Switching Time Waveform

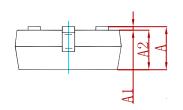
Fig.8 Gate Charge Waveform



#### **PACKAGE MECHANICAL DATA**

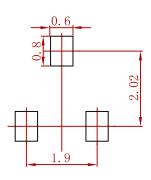






Symbol	Dimensions In Millimeters		Dimension	s In Inches
Зупьоі	Min	Max	Min	Max
Α	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
С	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
Е	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
е	0.950 TYP		0.03	7 TYP
e1	1.800	2.000	0.071	0.079
L	0.55	0 REF	0.022 REF	
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

### **Suggested Pad Layout**



- 1.Controlling dimension:in millimeters.2.General tolerance:± 0.05mm.3.The pad layout is for reference purposes only.

#### **REEL SPECIFICATION**

P/N	PKG	QTY
FDV302P	SOT-23	3000



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